

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	2078	charge near2 gain	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:03
S3	14	(charge near2 gain) with fail\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:05
S5	0	S3 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:05
S6	41	charge with gain with fail\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:05
S7	1	S6 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:09
S8	11328	stress\$4 with memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:16
S9	488	S8 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:18
S10	31	S8 and ((gray grey) near2 code)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:09

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S11	289	S8 and (transition\$4 same bits)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/08 13:52
S12	98	S8 and (transition\$4 same bits same address)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:17
S13	0	S12 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:17
S14	6	S11 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:19
S15	372	S8 and (transition\$4 same cycl\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:19
S16	28	S15 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:18
S17	85	S8 and (transition\$4 same cycl\$4 same address)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:20
S18	1	S17 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:22

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S19	10557	charge with gain	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:20
S20	0	S17 and S19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:20
S21	66	S17 and flash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:23
S22	120	cycl\$4 same address same stress\$4 same memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:22
S23	1	S22 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:22
S24	33	S22 and flash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:32
S25	46	stress\$4 with address with cycl\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:36
S26	7	stress\$4 with address with cycl\$4 with bit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:33

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S27	339	stress\$4 with cycl\$4 with pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:43
S28	43	S27 and flash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:37
S29	30	stress\$4 with address with pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:41
S30	68	("4267583" "4487705" "4553225" "4560959" "4701886" "4715034" "4744061" "4855688" "4858190" "4871963" "4879688" "4882702" "4916700" "4918378" "4969121" "5006787" "5034923" "5138619" "5173906" "5185722" "5198758" "5199034" "5265054" "5265100" "5285419" "5289475" "5295102" "5300840" "5341382" "5355340" "5381277" "5392005" "5396464" "5404331" "5407276" "5408435" "5424601" "5424988" "5428319" "5441011" "5446954" "5455542" "5459436" "5459733" "5467358" "5471428" "5471482" "5473284" "5473289" "5481229" "5488333" "5499600" "5500509" "5525936" "5530408" "5533196" "5543761" "5548252" "5557968" "5568084" "5574408" "5603570" "5604467" "5604468" "5607236" "5608359").PN. OR ("5883844"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/06/06 18:39
S31	1012	cycl\$4 with address with pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:42

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S32	4	(cycl\$4 with address with pattern) and (stress\$4 with memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:42
S33	242	cycl\$4 with address with pattern with bit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:43
S34	0	cycl\$4 with address with pattern with stress\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:43
S36	31	S27 and ("365" "711" "714").clas.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:44
S37	8672	(711/103,218 365/230.03,230.06 714/702,718).ccls.	USPAT	OR	ON	2007/06/08 13:58
S38	18	S37 and (charge with gain)	USPAT	OR	ON	2007/06/08 13:58

EAST Search History *Interference*

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L5	2262	(711/103,218 365/230.03,230.06 714/702,718).ccls.	US-PGPUB	OR	ON	2007/06/08 14:09
L6	278	(charge with gain).clm.	US-PGPUB	OR	ON	2007/06/08 14:10
L7	0	L5 and L6	US-PGPUB	OR	ON	2007/06/08 14:10
L8	138	(charge with fail\$4).clm.	US-PGPUB	OR	ON	2007/06/08 14:10
L9	1	L5 and L8	US-PGPUB	OR	ON	2007/06/08 14:10
L10	55	(gain with fail\$4).clm.	US-PGPUB	OR	ON	2007/06/08 14:10
L11	0	L5 and L10	US-PGPUB	OR	ON	2007/06/08 14:11
L12	137	(stress\$4 near2 signal).clm.	US-PGPUB	OR	ON	2007/06/08 14:11
L13	0	L5 and L12	US-PGPUB	OR	ON	2007/06/08 14:11
L14	624	(cycl\$4 near5 address).clm.	US-PGPUB	OR	ON	2007/06/08 14:11
L15	38	L5 and L14	US-PGPUB	OR	ON	2007/06/08 14:11
L16	402	(cycl\$4 near3 address).clm.	US-PGPUB	OR	ON	2007/06/08 14:11
L17	18	L5 and L16	US-PGPUB	OR	ON	2007/06/08 14:11

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charge gain failure

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Results 1 - 10 of about 1,640,000 for **charge gain failure**. (0.17 seconds)

Circuit for detecting both **charge gain** and **charge loss** properties ...

This unintentional **charge gain** or **charge loss** can change the memory state of the cell and become a cause of reliability **failure** in the Flash memory array. ...

www.patentstorm.us/patents/5912836-description.html - 39k - [Cached](#) - [Similar pages](#)

Charge gain stress test circuit for nonvolatile memory and test ...

A **charge gain** stress test circuit for a nonvolatile memory and a test method using the same ... <- Previous Patent (PCB adapter for IC chip **failure** ana. ...

www.freepatentsonline.com/6323671.html - 29k - [Cached](#) - [Similar pages](#)

HB 378 - As Introduced - **Failure** to disperse - increase penalty

Gain, possibly exceeding minimal in some jurisdictions ... Disorderly conduct is a more common **charge** than **failure** to disperse, however, it is usually used ...

www.lbo.state.oh.us/fiscal/fiscalnotes/124ga/HB0378IN.HTM - 38k - [Cached](#) - [Similar pages](#)

Turbo **charge** lighttpd with Linux AIO - **Gain** more performance ...

... you have achieved half your success; if you don't, you have achieved half your **failure**. ...

Turbo **charge** lighttpd with Linux AIO - **Gain** more performance ...

www.cyberciti.biz/tips/howto-increase-lighttpd-performance-with-linux-aio.html - 26k -

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ScienceDirect - Journal of Electrostatics : Electrostatic ...

Electrostatic discharge **failure** mechanism for cordless phone **charge** contacts*1 ... we hope to **gain** a better understanding of the mechanism responsible for ...

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[PDF] Recent developments on Flash memory reliability

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(a) and **charge gain** from the erased state (b). The corresponding band structures are also depicted. 3. Cell **failure** mechanisms ...

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» How to **gain** competitive advantage from IT | Paul Murphy | ZDNet.com

How to **gain** competitive advantage from IT ... getting the match wrong guarantees **failure**, but putting people with the right backgrounds in **charge** of systems ...

blogs.zdnet.com/Murphy/?p=600 - 51k - [Cached](#) - [Similar pages](#)

[PDF] An scr-switched, high voltage, high **gain** linear transformer system ...

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in the primary drivers. Such graceful **failure** could be an important feature in high reliability systems. **Charge** voltage with. 4. drivers charging a 32 nF ...

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[PDF] 19.0 Safety and Fault Analyses Postulation of Safety Issues ...

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Quick **charge** of LN2 with warm cryostat. Accident. Fire. Seismic. **Failure** of is fire retardant, and will limit heat **gain** and resulting pressurization ...

noyac3.psfc.mit.edu/bnlpulsed/safety.pdf - [Similar pages](#)

Reid makes abrupt ministry reshuffle in bid to gain control ...

But Dr Reid took the decision to put him in **charge** of immigration at the ... the Shadow

Home Secretary said: "This is clearly an admission of **failure** on the ...

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